

First Announcement

We are pleased to announce that the 16th XTOP Biennial Conference on High-Resolution X-Ray Diffraction and Imaging will be held in Karlsruhe, Germany.

The first XTOP conference was held in Marseille in 1992. With an initial focus on X-ray topography and high-resolution X-ray diffraction, the conference has always combined aspects of X-ray scattering and X-ray imaging. Over time, other related topics such as X-ray phase-contrast imaging, tomography and microscopy, and various scanning X-ray imaging techniques have been added.

Today, XTOP brings together scientists working on X-ray diffraction, reflection, grazing-incidence scattering, standing-waves, coherent diffraction, and ptychography techniques, as well as X-ray microtomography, microscopy and other imaging techniques based on phase, diffraction, scattering, or spectroscopic contrasts.

XTOP is a leading scientific conference on instrumentation, methods, and applications of laboratory and synchrotron-based X-ray diffraction and imaging techniques.

XTOP 2026 takes place in Karlsruhe, Germany from September 21 to 25, 2026.

Important Dates

Opening for the submission of abstracts: March 23, 2026

• Deadline for submission of abstracts: May 4, 2026

• Opening of the registration: beginning of April 2026

Early bird registration deadline: June 8, 2026

• Deadline for late registration: August 3, 2026

The local organizing committee is looking forward to welcoming you to Karlsruhe!